

MOSFET

Metal Oxide Semiconductor Field Effect Transistor

CoolMOS™ CFD2 650V Thinpak

650V CoolMOS™ CFD2 Power Transistor
IPL65R165CFD

Data Sheet

Rev. 2.0
Final

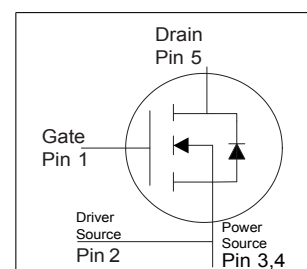
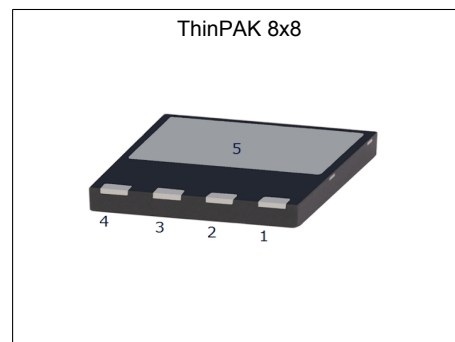
Industrial & Multimarket

1 Description

CoolMOS™ is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies. 650V CoolMOS™ CFD2 series combines the experience of the leading SJ MOSFET supplier with high class innovation. The resulting devices provide all benefits of a fast switching SJ MOSFET while offering an extremely fast and robust body diode. This combination of extremely low switching, commutation and conduction losses together with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler.

ThinPAK

ThinPAK is a new leadless SMD package for HV MOSFETs. The new package has a very small footprint of only 64mm² (vs. 150mm² for the D²PAK) and a very low profile with only 1mm height (vs. 4.4mm for the D²PAK). The significantly smaller package size, combined with benchmark low parasitic inductances, provides designers with a new and effective way to decrease system solution size in power-density driven designs.



Features

- Reduced board space consumption
- Increased power density
- Short commutation loop
- Smooth switching waveform
- Ultra-fast body diode
- Very high commutation ruggedness
- Extremely low losses due to very low FOM $R_{ds(on)} \cdot Q_g$ and E_{oss}
- Easy to use/drive
- Qualified for industrial grade applications according to JEDEC (J-STD20 and JESD22)
- Pb-free plating, Halogen free mold compound



Applications

650V CoolMOS™ CFD2 is especially suitable for resonant switching stages for e.g. PC Silverbox, LCD TV, Lighting, Server and Telecom.

Table 1 Key Performance Parameters

Parameter	Value	Unit
$V_{DS} @ T_{j,max}$	700	V
$R_{DS(on),max}$	0.165	Ω
Q_g,typ	86	nC
$I_D,pulse$	67	A
$E_{oss} @ 400V$	6.8	μJ
Body diode di/dt	900	A/ μs
Q_{rr}	0.7	μC
t_{rr}	140	ns
I_{rrm}	8.8	A

Type / Ordering Code	Package	Marking	Related Links
IPL65R165CFD	PG-VSON-4	65F6165	see Appendix A

Table of Contents

Description	2
Table of Contents	3
Maximum ratings	4
Thermal characteristics	5
Electrical characteristics	6
Electrical characteristics diagrams	8
Test Circuits	12
Package Outlines	13
Appendix A	14
Revision History	15
Disclaimer	15

2 Maximum ratings

at $T_j = 25^\circ\text{C}$, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current ¹⁾	I_D			21.3	A	$T_C = 25^\circ\text{C}$
				13.5		$T_C = 100^\circ\text{C}$
Pulsed drain current ²⁾	$I_{D,pulse}$			67	A	$T_C = 25^\circ\text{C}$
Avalanche energy, single pulse	E_{AS}			614	mJ	$I_D = 4.3\text{A}$, $V_{DD} = 50\text{V}$ (see table 10)
Avalanche energy, repetitive	E_{AR}			0.93	mJ	$I_D = 4.3\text{A}$, $V_{DD} = 50\text{V}$
Avalanche current, repetitive	I_{AR}			4.3	A	
MOSFET dv/dt ruggedness	dv/dt			50	V/ns	$V_{DS} = 0 \dots 400\text{V}$
Gate source voltage	V_{GS}	-20		20	V	static
		-30		30		AC ($f > 1\text{ Hz}$)
Operating and storage temperature	T_j, T_{stg}	-40		150	$^\circ\text{C}$	
Continuous diode forward current	I_S			21.3	A	$T_C = 25^\circ\text{C}$
Diode pulse current	$I_{S,pulse}$			67	A	$T_C = 25^\circ\text{C}$
Reverse diode dv/dt ³⁾	dv/dt			50	V/ns	$V_{DS} = 0 \dots 400\text{V}$, $I_{SD} \leq I_D$, $T_j = 25^\circ\text{C}$ (see table 8)
Maximum diode commutation speed	di/dt			900	A/ μs	
Power dissipation	P_{tot}			195	W	$T_C = 25^\circ\text{C}$

¹⁾ Limited by $T_{j,max}$.

²⁾ Pulse width t_p limited by $T_{j,max}$

³⁾ $V_{peak} < V_{(BR)DSS}$, $T_j < T_{j,max}$, identical low side and high side switch with same R_g

3 Thermal characteristics

Table 3 Thermal characteristics ThinPAK 8x8

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}			0.64	°C/W	
Thermal resistance, junction - ambient ¹⁾	R_{thJA}			62	°C/W	SMD version, device on PCB, minimal footprint
				45		SMD version, device on PCB, 6cm ² cooling area
Soldering temperature, wave- & reflowsoldering allowed	T_{sold}			260	°C	reflow MSL 3

¹⁾ Device on 40mm*40mm*1.5mm one layer epoxy PCB FR4 with 6cm² copper area (thickness 70µm) for drain connection. PCB is vertical without air stream cooling.

4 Electrical characteristics

at $T_j = 25^\circ\text{C}$, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(BR)DSS}$	650			V	$V_{GS} = 0V, I_D = 1mA$
Gate threshold voltage	$V_{GS(th)}$	3.5	4	4.5	V	$V_{DS} = V_{GS}, I_D = 0.9mA$
Zero gate voltage drain current	I_{DSS}			1	μA	$V_{DS} = 650V, V_{GS} = 0V, T_j = 25^\circ C$
			300			$V_{DS} = 650V, V_{GS} = 0V, T_j = 150^\circ C$
Gate-source leakage current	I_{GSS}			100	nA	$V_{GS} = 20V, V_{DS} = 0V$
Drain-source on-state resistance	$R_{DS(on)}$		0.149	0.165	Ω	$V_{GS} = 10V, I_D = 9.3A, T_j = 25^\circ C$
			0.386			$V_{GS} = 10V, I_D = 9.3A, T_j = 150^\circ C$
Gate resistance	R_G		1.5		Ω	$f = 1MHz$, open drain

Table 5 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}		2340		pF	$V_{GS} = 0V, V_{DS} = 100V, f = 1MHz$
Output capacitance	C_{oss}		110		pF	
Effective output capacitance, energy related ¹⁾	$C_{o(er)}$		90		pF	$V_{GS} = 0V, V_{DS} = 0 \dots 400V$
Effective output capacitance, time related ²⁾	$C_{o(tr)}$		420		pF	$I_D = \text{constant}, V_{GS} = 0V, V_{DS} = 0 \dots 400V$
Turn-on delay time	$t_{d(on)}$		12.4		ns	$V_{DD} = 400V, V_{GS} = 13V, I_D = 14.0A, R_G = 1.8\Omega$ (see table 9)
Rise time	t_r		7.6		ns	
Turn-off delay time	$t_{d(off)}$		52.8		ns	
Fall time	t_f		5.6		ns	

Table 6 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}		15		nC	$V_{DD} = 480V, I_D = 14A, V_{GS} = 0 \text{ to } 10V$
Gate to drain charge	Q_{gd}		47		nC	
Gate charge total	Q_g		86		nC	
Gate plateau voltage	$V_{plateau}$		6.4		V	

¹⁾ $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V

²⁾ $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V

Table 7 Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Diode forward voltage	V_{SD}		0.9		V	$V_{GS} = 0V$, $I_F = 14.0A$, $T_j = 25^{\circ}C$
Reverse recovery time	t_{rr}		140		ns	$V_R = 400V$, $I_F = 14.0A$, $di_F/dt = 100A/\mu s$ (see table 8)
Reverse recovery charge	Q_{rr}		0.7		μC	
Peak reverse recovery current	I_{rrm}		8.8		A	

5 Electrical characteristics diagrams

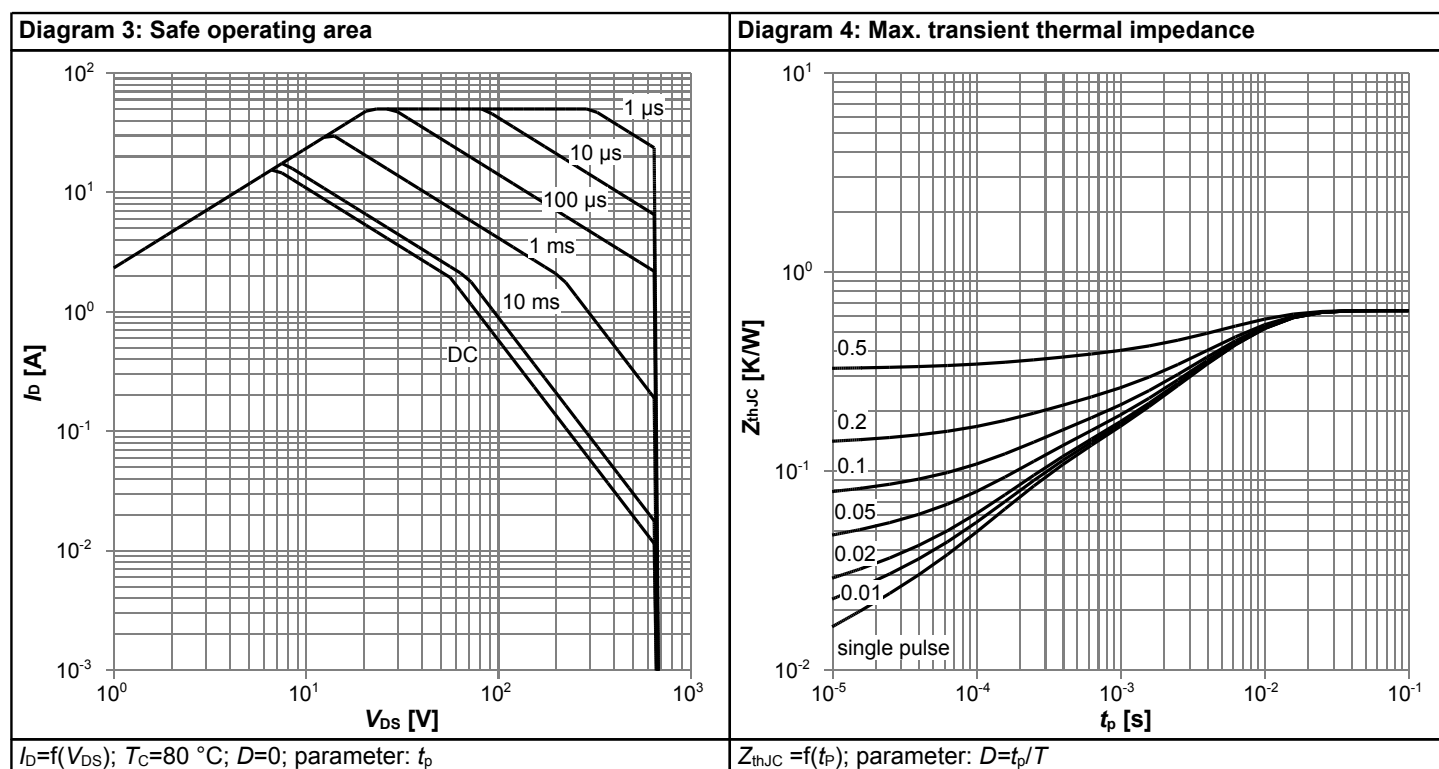
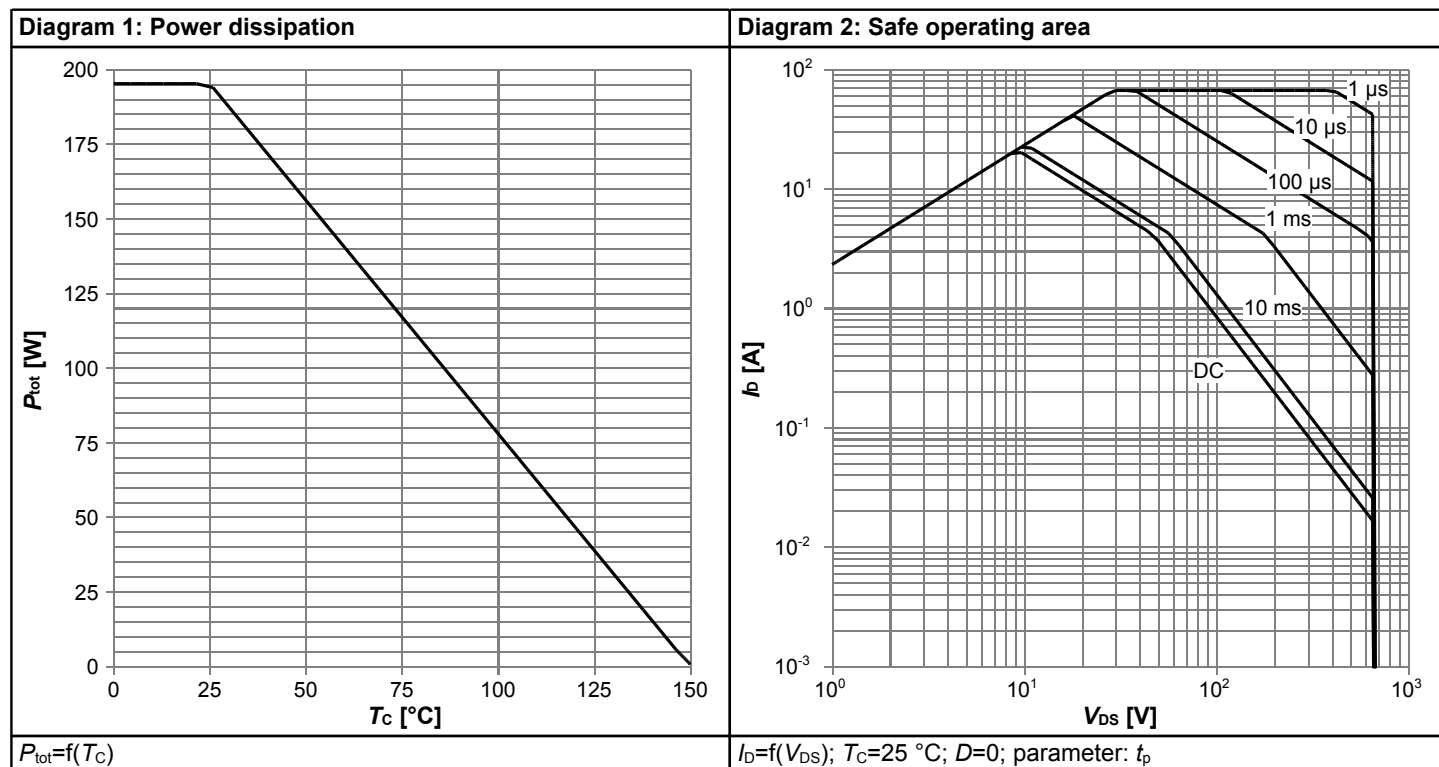


Diagram 5: Typ. output characteristics

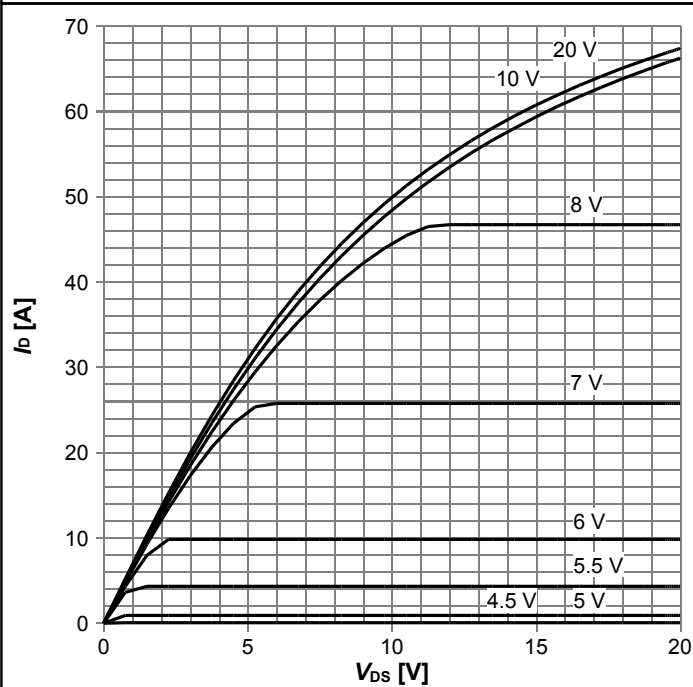

 $I_D = f(V_{DS}); T_J = 25^\circ\text{C}; \text{parameter: } V_{GS}$

Diagram 6: Typ. output characteristics

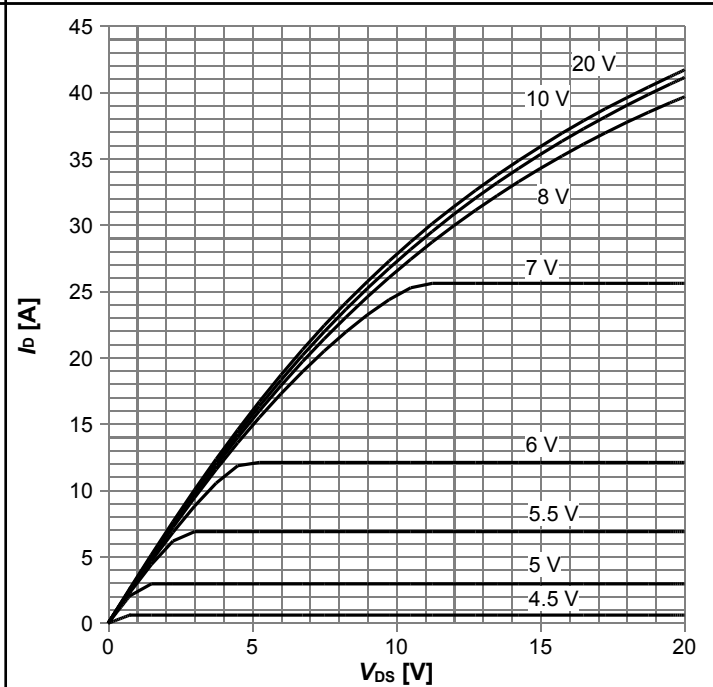

 $I_D = f(V_{DS}); T_J = 125^\circ\text{C}; \text{parameter: } V_{GS}$

Diagram 7: Typ. drain-source on-state resistance

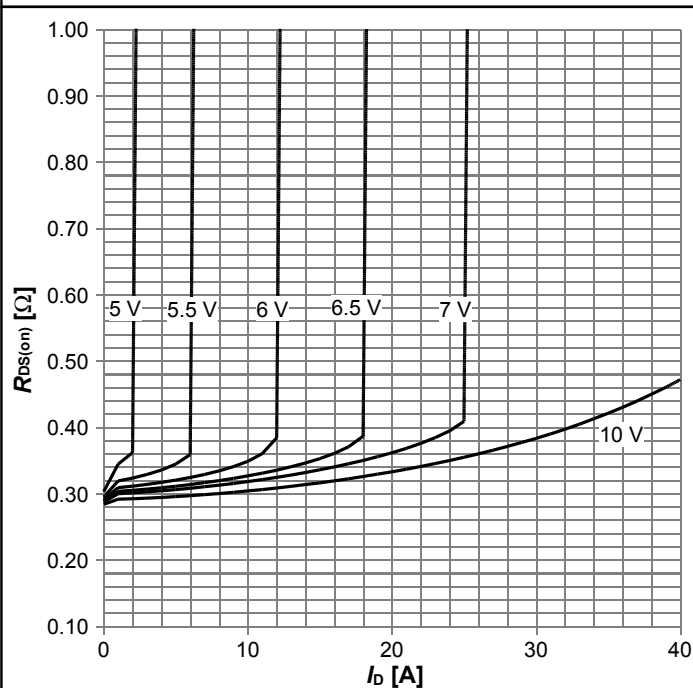

 $R_{DS(on)} = f(I_D); T_J = 125^\circ\text{C}; \text{parameter: } V_{GS}$

Diagram 8: Drain-source on-state resistance

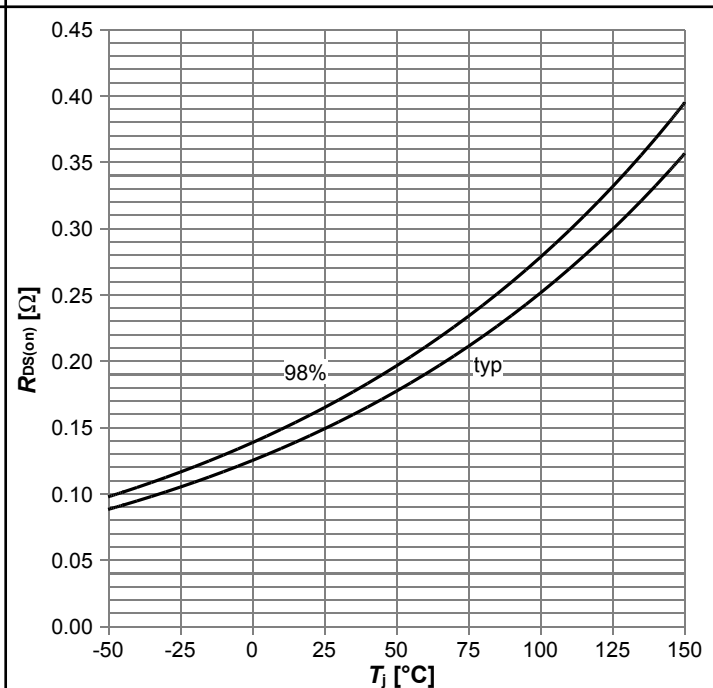

 $R_{DS(on)} = f(T_J); I_D = 9.3\text{ A}; V_{GS} = 10\text{ V}$

Diagram 9: Typ. transfer characteristics

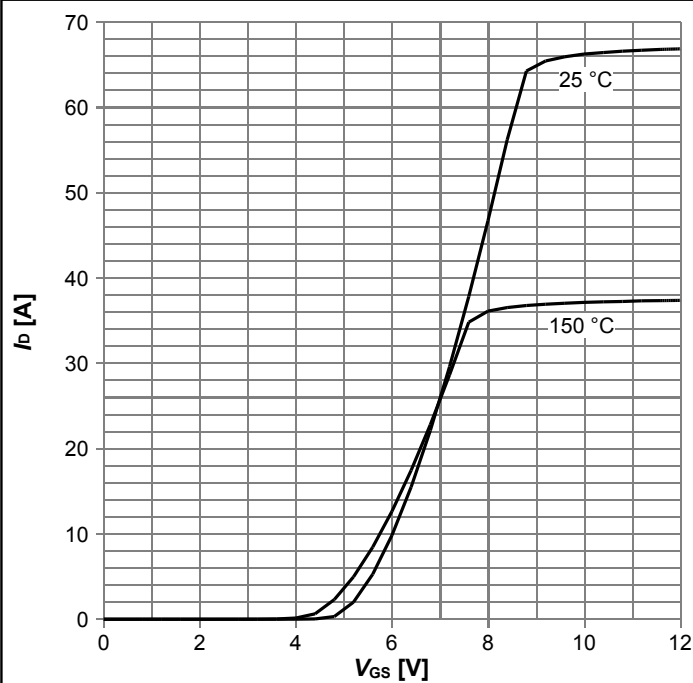

 $I_D = f(V_{GS}); V_{DS} = 20V; \text{parameter: } T_j$

Diagram 10: Typ. gate charge

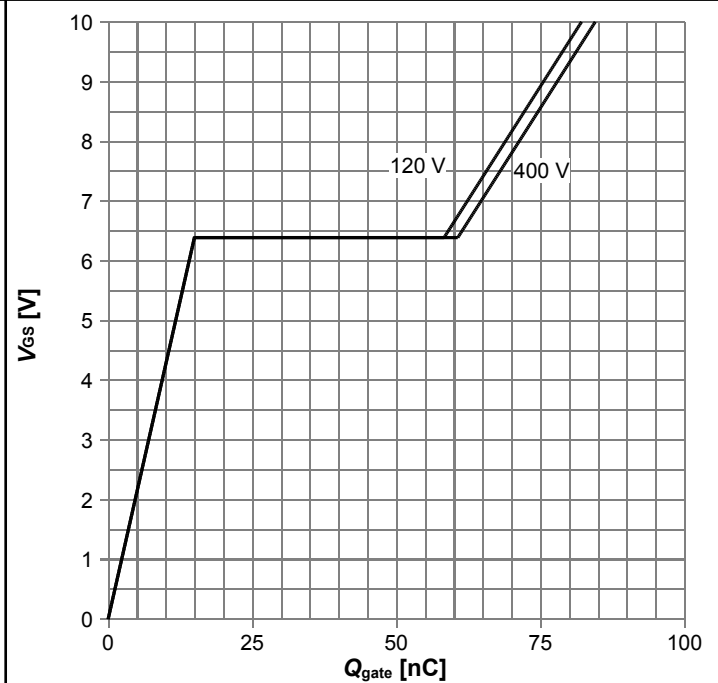

 $V_{GS} = f(Q_{gate}); I_D = 14 \text{ A pulsed}; \text{parameter: } V_{DD}$

Diagram 11: Forward characteristics of reverse diode

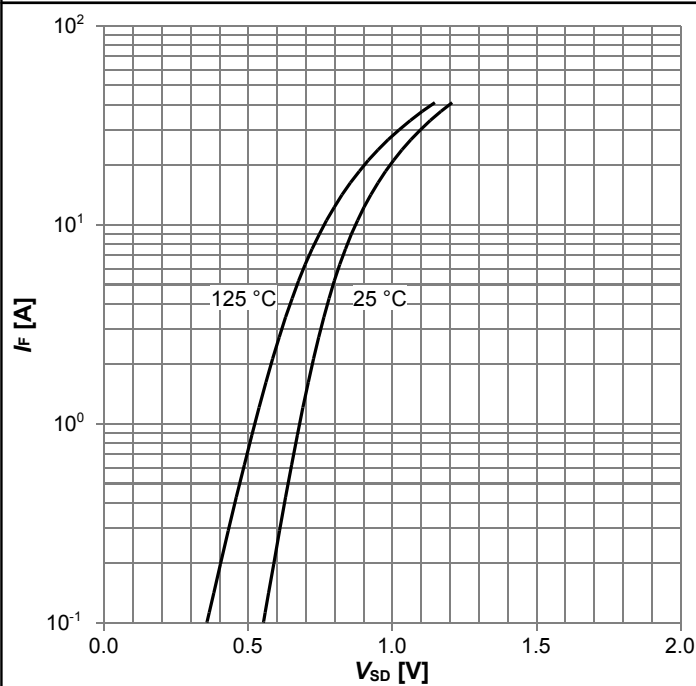

 $I_F = f(V_{SD}); \text{parameter: } T_j$

Diagram 12: Avalanche energy

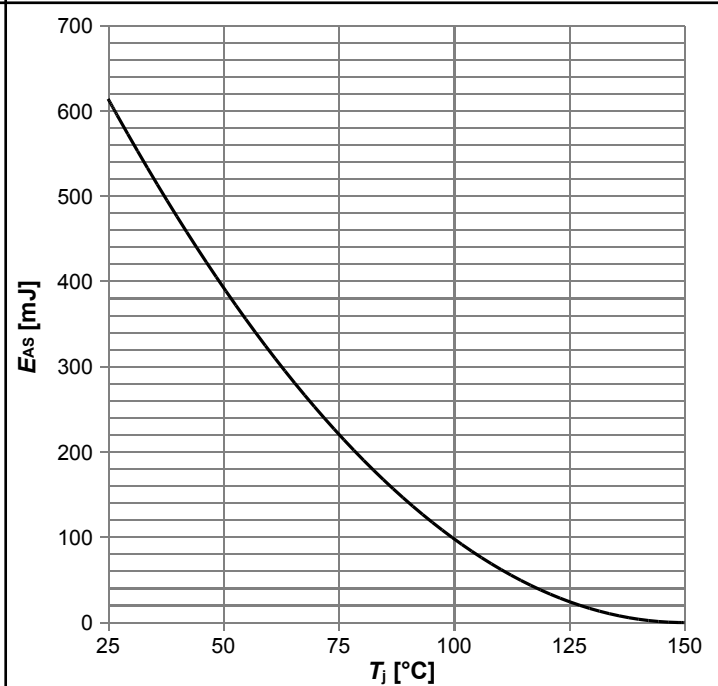
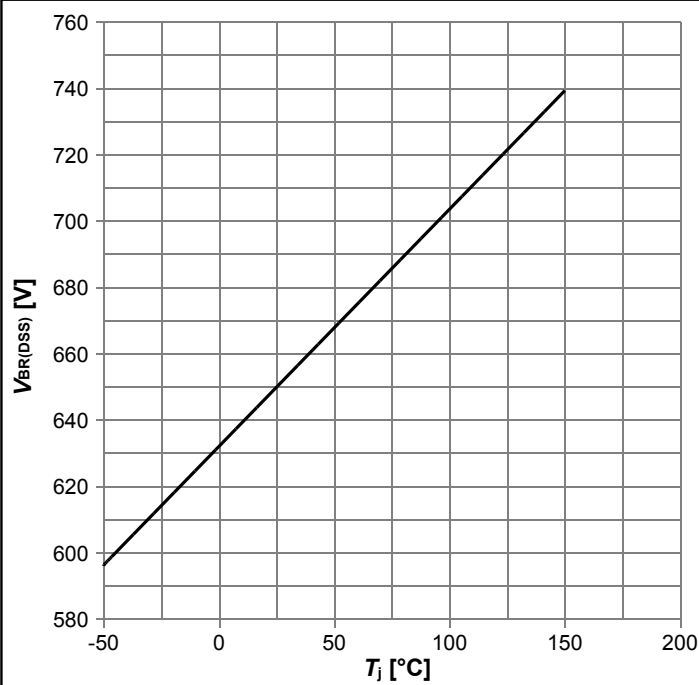
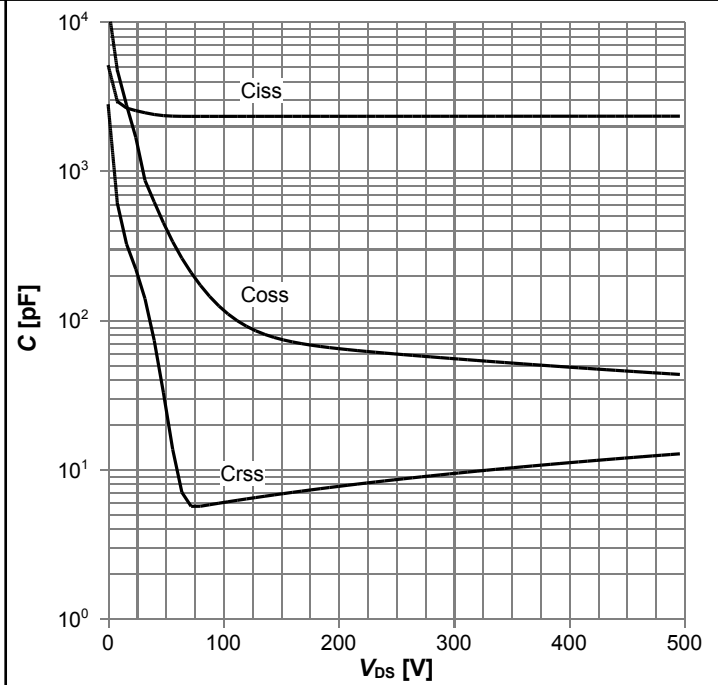

 $E_{AS} = f(T_j); I_D = 4.3 \text{ A}; V_{DD} = 50 \text{ V}$

Diagram 13: Drain-source breakdown voltage



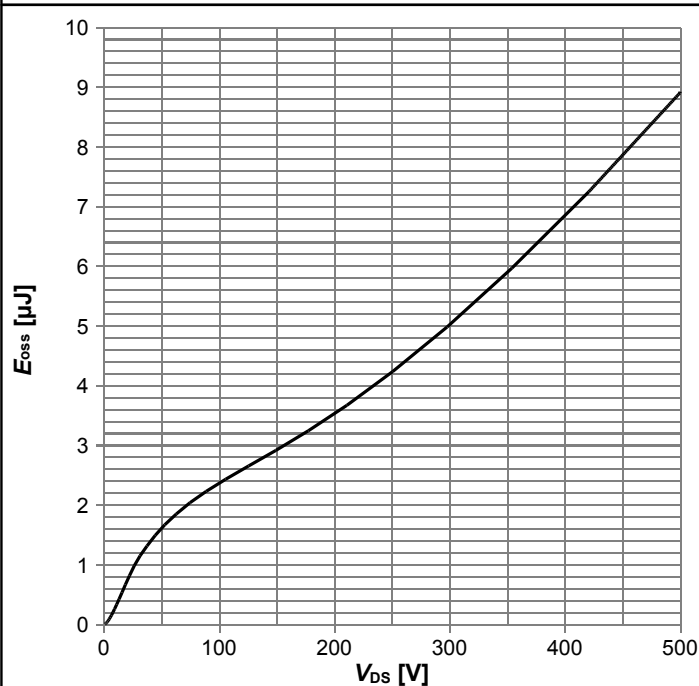
$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$

Diagram 14: Typ. capacitances



$$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$$

Diagram 15: Typ. Coss stored energy



$$E_{oss} = f(V_{DS})$$

6 Test Circuits

Table 8 Diode characteristics

Test circuit for diode characteristics

$R_{g1} = R_{g2}$

Diode recovery waveform

$t_{rr} = t_F + t_S$
 $Q_{rr} = Q_F + Q_S$

Table 9 Switching times

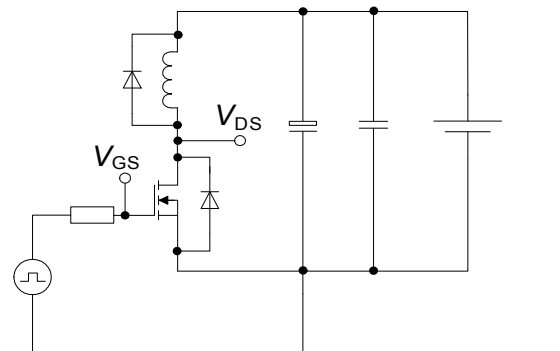
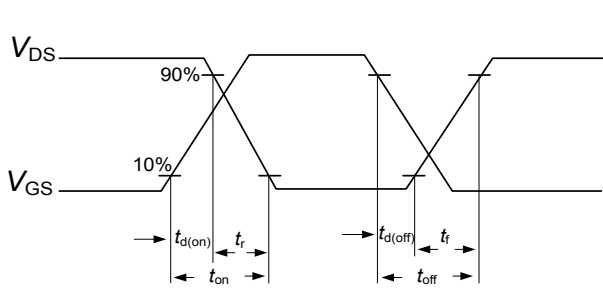
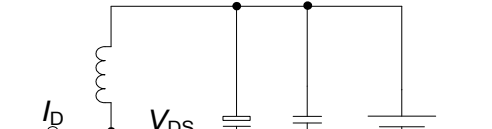
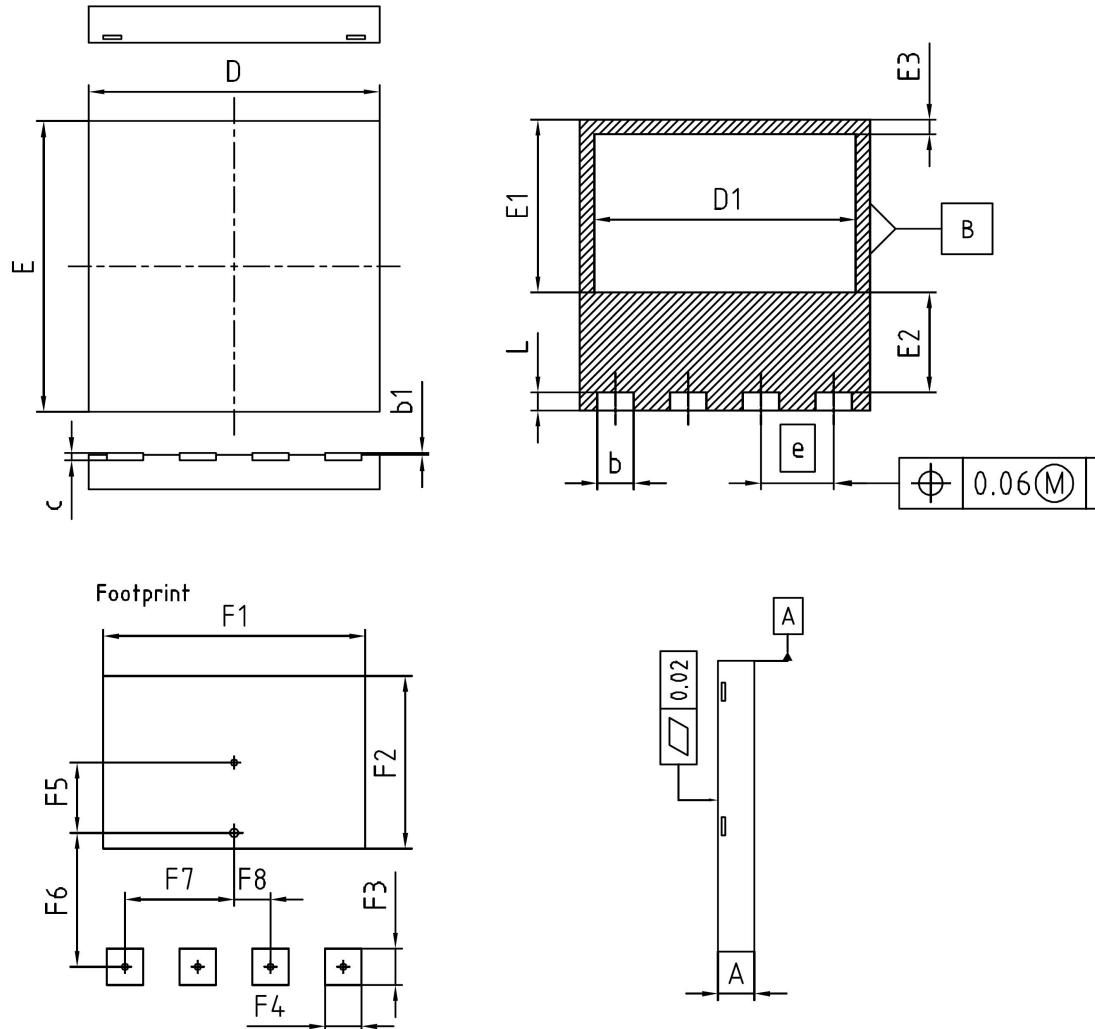
Switching times test circuit for inductive load	Switching times waveform
 The circuit diagram shows a MOSFET switching an inductive load. A pulse generator is connected to the gate of the MOSFET through a resistor. The drain of the MOSFET is connected to an inductor and a diode in parallel, which is then connected to a DC supply. The source of the MOSFET is connected to ground. The drain-source voltage is labeled V_{DS} and the gate-source voltage is labeled V_{GS}. The inductor is represented by a coil symbol, and the diode is shown in parallel with it, pointing towards the MOSFET drain.	 The waveform diagram shows the drain-source voltage V_{DS} and gate-source voltage V_{GS} during switching. The V_{GS} signal is a square wave that transitions between a high level and a low level. The V_{DS} signal shows the voltage across the MOSFET during these transitions. Key time intervals are marked: $t_{d(on)}$ (delay time to turn on), t_r (rise time), $t_{d(off)}$ (delay time to turn off), and t_f (fall time). The 90% and 10% voltage levels are indicated for the rise and fall times. The total time the MOSFET is in the linear region is labeled t_{on} and t_{off}.

Table 10 Unclamped inductive load

Unclamped inductive load test circuit	Unclamped inductive waveform
	

7 Package Outlines



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0.90	1.10	0.035	0.043
b	0.90	1.10	0.035	0.043
b1	0.00	0.05	0.000	0.002
c	0.10	0.30	0.004	0.012
D	7.90	8.10	0.311	0.319
D1	7.10	7.30	0.280	0.287
E	7.90	8.10	0.311	0.319
E1	4.65	4.85	0.183	0.191
E2	2.65	2.85	0.104	0.112
E3	0.30	0.50	0.012	0.020
e	2.00 (BSC)		0.079 (BSC)	
L	0.40	0.60	0.016	0.024
N	4		4	
F1	7.20		0.283	
F2	4.75		0.187	
F3	1.00		0.039	
F4	1.00		0.039	
F5	1.43		0.056	
F6	4.20		0.165	
F7	3.00		0.118	
F8	1.00		0.039	

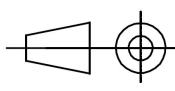
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EUROPEAN PROJECTION 
ISSUE DATE 05-04-2010
REVISION 01

Figure 1 Outline PG-VSON-4, dimensions in mm/inches

8 Appendix A

Table 11 Related Links

- IFX Design Tools: www.infineon.com
- IFX CoolMOS Webpage: www.infineon.com

Revision History

IPL65R165CFD

Revision: 2014-03-19, Rev. 2.0

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2014-03-19	Release of final version

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